

FORM PTO-1449

## INFORMATION DISCLOSURE STATEMENT

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APPLICANT: CHEN et al.

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GROUP: 2811



## U.S. PATENT DOCUMENTS

INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA1					
	AB1					
	AC1					
	AD1					
	AE1					
	AF1					

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AG1					Yes No
	AH1					Yes No
	AI1					Yes No

## OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

	AJ	1	
	AK	1	Schroder, Dieter K., "Semiconductor Material and Device Characterization", Fig. E6.5(a), Oxide failure modes, John Wiley & Sons, Inc., 2 <sup>nd</sup> Edition, p391, (1998)
	AL	1	Schroder, Dieter K., "Semiconductor Material and Device Characterization", Fig. 6.40, Charge-to-breakdown as a function of oxide thickness, John Wiley & Sons, Inc., 2 <sup>nd</sup> Edition, p397, (1998)

EXAMINER

DATE CONSIDERED

8/30/02

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.